

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 09/669,354 ISHIYAMA, HISANOBU.	
		Examiner Hau H Nguyen	Art Unit 2674	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-5852425	12-1998	Bird et al.	345
B	US-5420600	05-1995	Strobel et al.	345
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
U	S-MOS System, Inc., Dot Matrix LCD Driver SED1520/21, Version 1.0 (Preliminary) October, 1996 http://shellyinc.com/conchips/SED1520.pdf		
V			
W			
X			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination ISHIYAMA, HISANOBU	
		Examiner Hau H Nguyen	Art Unit 2674	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-5852425	12-1998	Bird et al.	345
B	US-5420600	05-1995	Strobel et al.	345
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages		
U	S-MOS System, Inc., Dot Matrix LCD Driver SED1520/21, Version 1.0 (Preliminary) October, 1996		
V			
W			
X			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.